## Notice of References Cited Application/Control No. 10/849,186 Examiner John S. Chu Applicant(s)/Patent Under Reexamination WATANABE ET AL Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2005/0095527 A1	05-2005	Yokoyama et al.	430/270.1
	В	US-			
	С	US-	<u> </u>		
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	н	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification ,
	·N					
	0					
	Р					
	Ω					
	R					
	S					
	T		·			

## NON-PATENT DOCUMENTS

_						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	٧					
	W					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.